

## Description

The ZXMN3A06DN8TA uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

# D1b1<sub>D2</sub> D2 S1<sub>G1</sub> S2<sub>G2</sub> SOP-8

#### **General Features**

 $V_{DS} = 30V \ I_D = 6A$   $R_{DS(ON)} < 30m\Omega \ @ V_{GS} = 10 \ V$   $R_{DS(ON)} < 42m\Omega \ @ V_{GS} = 4.5V$ 

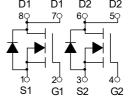
## (SOIC-8)

### **Application**

Battery protection

Load switch

Uninterruptible power supply



**Dual N-Channel MOSFET** 

#### **Package Marking and Ordering Information**

Product ID	Pack	Brand	Qty(PCS)
ZXMN3A06DN8TA	SOP-8(SOIC-8)	HXY MOSFET	3000

#### Absolute Maximum Ratings@T<sub>i</sub>=25°C(unless otherwise specified)

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	30	V
V <sub>G</sub> s	Gate-Source Voltage	<u>+</u> 20	V
I <sub>D</sub> @T <sub>A</sub> =25°C	Drain Current, V <sub>GS</sub> @ 4.5V <sup>3</sup>	6	А
I <sub>D</sub> @T <sub>A</sub> =70°C	Drain Current, V <sub>GS</sub> @ 4.5V <sup>3</sup>	5	А
Ірм	Pulsed Drain Current <sup>1</sup>	30	А
PD@TA=25°C	Total Power Dissipation	2	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Rthj-a	Maximum Thermal Resistance, Junction- ambient <sup>3</sup>	62.5	°C/W

## Dual N-Channel Enhancement Mode MOSFET

#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter Parameter	Conditions		Min	Тур	Max	Units
Static Pa	Static Parameters						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$		30			V
I <sub>DSS</sub> Z	Zero Gate Voltage Drain Current	$V_{DS}$ =30V, $V_{GS}$ =0V				1	μΑ
.033	Zere Gate Veltage Brain Garrent		T <sub>J</sub> =55°C			5	μιτ
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=250\mu A$		1.2	1.8	2.4	V
$I_{D(ON)}$	On state drain current	$V_{GS}$ =10V, $V_{DS}$ =5V		30			Α
		$V_{GS}$ =10V, $I_D$ =6A			25	30	mΩ
$R_{DS(ON)}$	Static Drain-Source On-Resistance		T <sub>J</sub> =125°C		40	48	11122
		$V_{GS}$ =4.5V, $I_D$ =5A			33	42	mΩ
<b>9</b> FS	Forward Transconductance	$V_{DS}=5V$ , $I_{D}=6A$			15		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V			0.76	1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Curre	irrent				2.5	Α
Dynamic	Parameters						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz			255	310	pF
C <sub>oss</sub>	Output Capacitance				45		pF
$C_{rss}$	Reverse Transfer Capacitance				35	50	pF
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		1.6	3.25	4.9	Ω
Switching	Switching Parameters						
Q <sub>g(10V)</sub>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =6A			5.2	6.3	nC
Qg <sub>(4.5V)</sub>					2.55	3.2	nC
$Q_{gs}$	Gate Source Charge				0.85		nC
$Q_{gd}$	Gate Drain Charge				1.3		nC
t <sub>D(on)</sub>	Turn-On DelayTime				4.5		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $R_L$ =2.5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			2.5		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				14.5		ns
t <sub>f</sub>	Turn-Off Fall Time				3.5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =6A, dI/dt=100A/μs			8.5		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =6A, dI/dt=100A/μs	;		2.2		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on  $1 \text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25°C. The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =150°C, using  $\leq$  10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150$ °C. Ratings are based on low frequency and duty cycles to keep initial  $T_J=25$ °C.

D. The  $R_{\theta JA}$  is the sum of the thermal impedence from junction to lead  $R_{\theta JL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 $\mu$ s pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedence which is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(MAX)}=150$ °C. The SOA curve provides a single pulse ratin g.



#### **Typical Electrical And Thermal Characteristics**

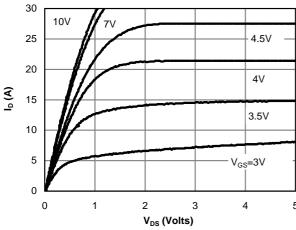
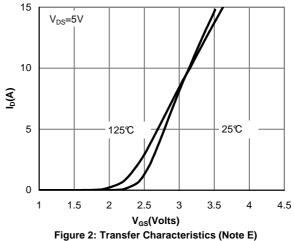


Fig 1: On-Region Characteristics (Note E)



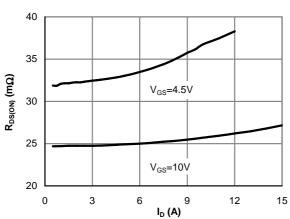


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

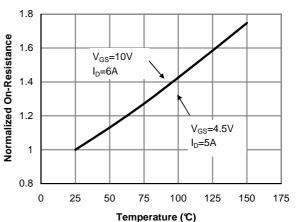


Figure 4: On-Resistance vs. Junction Temperature (Note E)

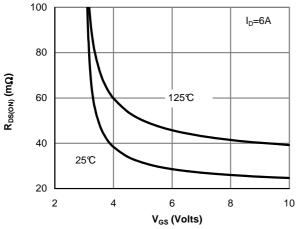


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

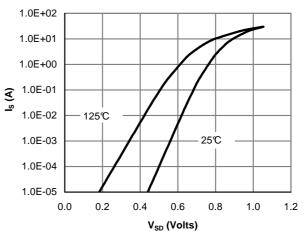


Figure 6: Body-Diode Characteristics (Note E)

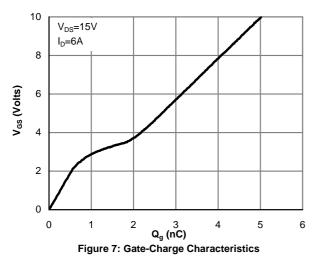
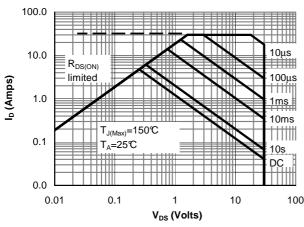


Figure 8: Capacitance Characteristics



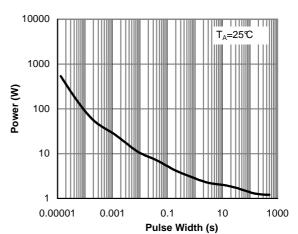


Figure 10: Maximum Forward Biased Safe Operating Area (Note F)

Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note F)

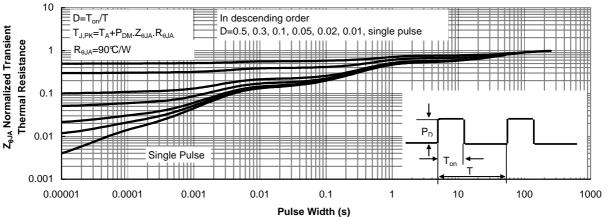
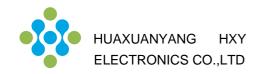
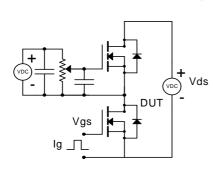
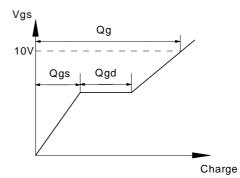


Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

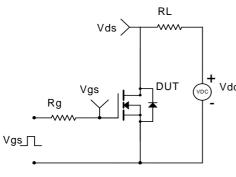


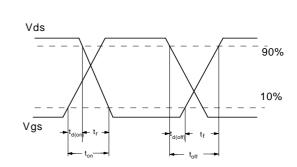
#### Gate Charge Test Circuit & Waveform



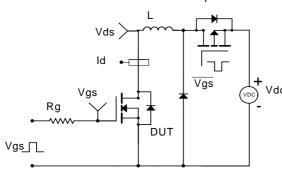


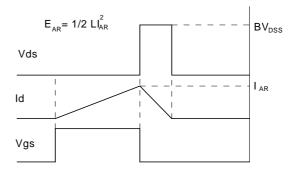
Resistive Switching Test Circuit & Waveforms



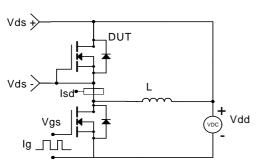


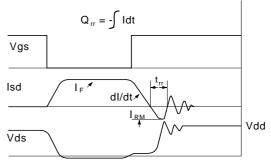
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

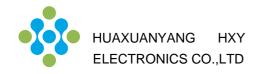




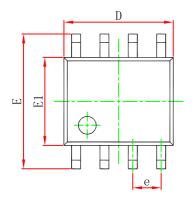
#### Diode Recovery Test Circuit & Waveforms

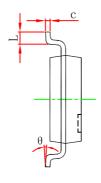


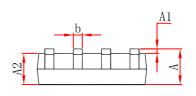




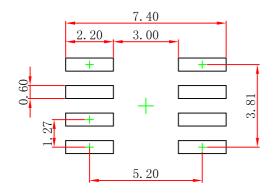
### **SOP-8(SOIC-8) Package Outline Dimensions**







Symbol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1. 350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
c	0.170	0.250	0.007	0.010	
D	4.800	5.000	0.189	0. 197	
e	1. 270 (	1.270 (BSC)		(BSC)	
E	5.800	6.200	0. 228	0.244	
E1	3.800	4.000	0.150	0.157	
L	0.400	1.270	0.016	0.050	
θ	0°	8°	0°	8°	



- Note: 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
  3.The pad layout is for reference purposes only.



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